

<b>Notice of References Cited</b>	Application/Control No. 10/021,895		Applicant(s)/Patent Under Reexamination SUN ET AL.	
	Examiner Carol S. Tsai		Art Unit 2857	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0111536	05-2005	Cranford et al.	375/226
*	B	US-2005/0080574	04-2005	Draving, Steven D.	702/069
*	C	US-2005/0027477	02-2005	Li et al.	702/181
*	D	US-2004/0136450	07-2004	Guenther, Mark L.	375/226
*	E	US-2004/0019458	01-2004	Jang, Jin-Mo	702/182
*	F	US-2003/0115017	06-2003	Sun et al.	702/181
*	G	US-2001/0044704	11-2001	Li et al.	702/180
*	H	US-6,888,457	05-2005	Wilkinson et al.	340/540
*	I	US-6,853,933	02-2005	Tan et al.	702/76
*	J	US-6,832,172	12-2004	Ward et al.	702/69
*	K	US-6,799,144	09-2004	Li et al.	702/180
*	L	US-6,622,117	09-2003	Deligne et al.	702/190
*	M	US-5,495,409	02-1996	Kanno, Yuji	700/79

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.